# Quad Analog Switch/ Multiplexer/Demultiplexer High-Performance Silicon-Gate CMOS

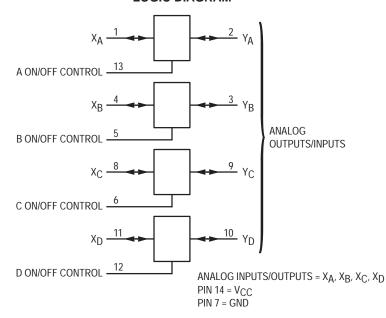
The MC74LVX4066 utilizes silicon–gate CMOS technology to achieve fast propagation delays, low ON resistances, and low OFF-channel leakage current. This bilateral switch/multiplexer/demultiplexer controls analog and digital voltages that may vary across the full power–supply range (from VCC to GND).

The LVX4066 is identical in pinout to the metal–gate CMOS MC14066 and the high–speed CMOS HC4066A. Each device has four independent switches. The device has been designed so that the ON resistances (R<sub>ON</sub>) are much more linear over input voltage than R<sub>ON</sub> of metal–gate CMOS analog switches.

The ON/OFF control inputs are compatible with standard CMOS outputs; with pull-up resistors, they are compatible with LSTTL outputs.

- Fast Switching and Propagation Speeds
- High ON/OFF Output Voltage Ratio
- Low Crosstalk Between Switches
- Diode Protection on All Inputs/Outputs
- Wide Power–Supply Voltage Range  $(V_{CC} GND) = 2.0$  to 6.0 Volts
- Analog Input Voltage Range  $(V_{CC} GND) = 2.0$  to 6.0 Volts
- Improved Linearity and Lower ON Resistance over Input Voltage than the MC14016 or MC14066
- Low Noise
- Chip Complexity: 44 FETs or 11 Equivalent Gates

#### LOGIC DIAGRAM





#### ON Semiconductor

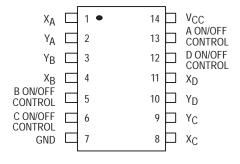
Formerly a Division of Motorola http://onsemi.com





14-LEAD SOIC D SUFFIX CASE 751A 14-LEAD TSSOP DT SUFFIX CASE 948G

## PIN CONNECTION AND MARKING DIAGRAM (Top View)



For detailed package marking information, see the Marking Diagram section on page 10 of this data sheet.

#### ORDERING INFORMATION

Device	Package	Shipping
MC74LVX4066D	SOIC	55 Units/Rail
MC74LVX4066DT	TSSOP	96 Units/Rail

#### **FUNCTION TABLE**

On/Off Control	State of
Input	Analog Switch
L	Off
H	On

#### **MAXIMUM RATINGS\***

Symbol	Parameter	Value	Unit
VCC	Positive DC Supply Voltage (Referenced to GND)	- 0.5 to + 7.0	V
VIS	Analog Input Voltage (Referenced to GND)	$-0.5$ to $V_{CC} + 0.5$	V
V <sub>in</sub>	Digital Input Voltage (Referenced to GND)	$-0.5$ to $V_{CC} + 0.5$	V
l <sub>in</sub>	DC Current Into or Out of ON/OFF Control Pins	± 20	mA
Is	DC Current Into or Out of Switch Pins	± 20	mA
PD	Power Dissipation in Still Air, SOIC Package† TSSOP Package†	500 450	mW
T <sub>stg</sub>	Storage Temperature	- 65 to + 150	°C
TL	Lead Temperature, 1 mm from Case for 10 Seconds	260	°C

<sup>\*</sup>Maximum Ratings are those values beyond which damage to the device may occur.

#### RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter		Min	Max	Unit
VCC	Positive DC Supply Voltage (Referenced to GND)		2.0	6.0	V
VIS	Analog Input Voltage (Referenced to GND)			Vcc	V
V <sub>in</sub>	Digital Input Voltage (Referenced to GND)			Vcc	V
V <sub>IO</sub> *	Static or Dynamic Voltage Across Switch			1.2	V
TA	Operating Temperature, All Package Types		- 55	+ 85	°C
t <sub>r</sub> , t <sub>f</sub>	Input Rise and Fall Time, ON/OFF Control Inputs (Figure 10) $ \begin{array}{c} \text{V}_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V} \\ \text{V}_{CC} = 5.0 \text{ V} \pm 0.5 \text{ V} \end{array} $			100 20	ns/V

<sup>\*</sup>For voltage drops across the switch greater than 1.2 V (switch on), excessive VCC current may be drawn; i.e., the current out of the switch may contain both V<sub>CC</sub> and switch input components. The reliability of the device will be unaffected unless the Maximum Ratings are exceeded.

#### DC ELECTRICAL CHARACTERISTIC Digital Section (Voltages Referenced to GND)

				Gu	aranteed Li	mit	
Symbol	Parameter	Test Conditions	V <sub>CC</sub>	– 55 to 25°C	≤ 85°C	≤ 125°C	Unit
VIH	Minimum High-Level Voltage ON/OFF Control Inputs (Note 1)	R <sub>on</sub> = Per Spec	2.0 3.0 4.5 5.5	1.5 2.1 3.15 3.85	1.5 2.1 3.15 3.85	1.5 2.1 3.15 3.85	V
V <sub>IL</sub>	Maximum Low–Level Voltage ON/OFF Control Inputs (Note 1)	R <sub>on</sub> = Per Spec	2.0 3.0 4.5 5.5	0.5 0.9 1.35 1.65	0.5 0.9 1.35 1.65	0.5 0.9 1.35 1.65	V
l <sub>in</sub>	Maximum Input Leakage Current ON/OFF Control Inputs	V <sub>in</sub> = V <sub>CC</sub> or GND	5.5V	± 0.1	± 1.0	± 1.0	μА
Icc	Maximum Quiescent Supply Current (per Package)	V <sub>in</sub> = V <sub>CC</sub> or GND V <sub>IO</sub> = 0 V	5.5	4.0	40	160	μΑ

<sup>1.</sup> Specifications are for design target only. Not final specification limits.

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high-impedance circuit. For proper operation, Vin and Vout should be constrained to the range GND  $\leq$  (V<sub>in</sub> or V<sub>out</sub>)  $\leq$  V<sub>CC</sub>.

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or VCC). Unused outputs must be left open. I/O pins must be connected to a properly terminated line or bus.

Functional operation should be restricted to the Recommended Operating Conditions. †Derating — SOIC Package: - 7 mW/°C from 65° to 125°C

TSSOP Package: - 6.1 mW/°C from 65° to 125°C

#### DC ELECTRICAL CHARACTERISTICS Analog Section (Voltages Referenced to GND)

				Gu	aranteed Li	mit	
Symbol	Parameter	Test Conditions	V <sub>CC</sub>	– 55 to 25°C	≤ 85°C	≤ 125°C	Unit
R <sub>on</sub>	Maximum "ON" Resistance	$V_{\text{in}} = V_{\text{IH}}$ $V_{\text{IS}} = V_{\text{CC}}$ to GND $ I_{\text{S}}  \le 10$ mA (Figures 1, 2)	2.0† 3.0 4.5 5.5	— 30 25 20	— 35 30 25	 40 35 30	Ω
		$V_{\text{IN}} = V_{\text{IH}}$ $V_{\text{IS}} = V_{\text{CC}}$ or GND (Endpoints) $ I_{\text{S}}  \le 10 \text{ mA}$ (Figures 1, 2)	2.0 3.0 4.5 5.5	— 30 25 20	— 35 30 25	— 40 35 30	
ΔR <sub>on</sub>	Maximum Difference in "ON" Resistance Between Any Two Channels in the Same Package	$V_{IN} = V_{IH}$ $V_{IS} = 1/2 (V_{CC} - GND)$ $I_{S} \le 2.0 \text{ mA}$	3.0 4.5 5.5	15 10 10	20 12 12	25 15 15	Ω
l <sub>off</sub>	Maximum Off–Channel Leakage Current, Any One Channel	V <sub>IO</sub> = V <sub>IL</sub> V <sub>IO</sub> = V <sub>CC</sub> or GND Switch Off (Figure 3)	5.5	0.1	0.5	1.0	μА
I <sub>on</sub>	Maximum On–Channel Leakage Current, Any One Channel	V <sub>in</sub> = V <sub>IH</sub> V <sub>IS</sub> = V <sub>CC</sub> or GND (Figure 4)	5.5	0.1	0.5	1.0	μΑ

 $<sup>\</sup>dagger$ At supply voltage (V<sub>CC</sub>) approaching 2 V the analog switch-on resistance becomes extremely non-linear. Therefore, for low-voltage operation, it is recommended that these devices only be used to control digital signals (See Figure 1a).

#### AC ELECTRICAL CHARACTERISTICS ( $C_L = 50$ pF, ON/OFF Control Inputs: $t_f = t_f = 6$ ns)

			Gu	aranteed Li	mit	
Symbol	Parameter	V <sub>CC</sub>	– 55 to 25°C	≤ 85°C	≤ 125°C	Unit
t <sub>PLH</sub> , t <sub>PHL</sub>	Maximum Propagation Delay, Analog Input to Analog Output (Figures 8 and 9)	2.0 3.0 4.5 5.5	4.0 3.0 1.0 1.0	6.0 5.0 2.0 2.0	8.0 6.0 2.0 2.0	ns
tPLZ, tPHZ	Maximum Propagation Delay, ON/OFF Control to Analog Output (Figures 10 and 11)	2.0 3.0 4.5 5.5	30 20 15 15	35 25 18 18	40 30 22 20	ns
<sup>t</sup> PZL <sup>,</sup> <sup>†</sup> PZH	Maximum Propagation Delay, ON/OFF Control to Analog Output (Figures 10 and 1 1)	2.0 3.0 4.5 5.5	20 12 8.0 8.0	25 14 10 10	30 15 12 12	ns
С	Maximum Capacitance  ON/OFF Control Input  Control Input = GND  Analog I/O  Feedthrough	_ _ _	10 35 1.0	10 35 1.0	10 35 1.0	pF
			Typical	@ 25°C, V <sub>C</sub> (	C = 5.0 V	

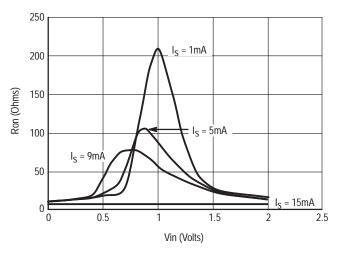
		Typical @ 25°C, V <sub>CC</sub> = 5.0 V	
$C_{PD}$	Power Dissipation Capacitance (Per Switch) (Figure 13)*	15	pF

<sup>\*</sup> Used to determine the no–load dynamic power consumption:  $P_D = C_{PD} V_{CC}^2 f + I_{CC} V_{CC}$ .

### ADDITIONAL APPLICATION CHARACTERISTICS (Voltages Referenced to GND Unless Noted)

Symbol	Parameter	Test Conditions	V <sub>CC</sub>	Limit* 25°C	Unit
BW	Maximum On–Channel Bandwidth or Minimum Frequency Response (Figure 5)	$\begin{aligned} f_{\text{in}} &= 1 \text{ MHz Sine Wave} \\ &\text{Adjust } f_{\text{in}} \text{ Voltage to Obtain 0 dBm at V}_{\text{OS}} \\ &\text{Increase } f_{\text{in}} \text{ Frequency Until dB Meter Reads} - 3 \text{ dB} \\ &\text{R}_{\text{L}} &= 50 \Omega, \text{ C}_{\text{L}} = 10 \text{ pF} \end{aligned}$	4.5 5.5	150 160	MHz
_	Off–Channel Feedthrough Isolation (Figure 6)	$ \begin{aligned} f_{\text{in}} &\equiv \text{Sine Wave} \\ \text{Adjust } f_{\text{in}} &\text{ Voltage to Obtain 0 dBm at V}_{\text{IS}} \\ f_{\text{in}} &= 10 \text{ kHz}, \text{ R}_{\text{L}} = 600 \ \Omega, \text{ C}_{\text{L}} = 50 \text{ pF} \end{aligned} $	4.5 5.5	- 50 - 50	dB
		$f_{in}$ = 1.0 MHz, $R_L$ = 50 $\Omega$ , $C_L$ = 10 pF	4.5 5.5	- 37 - 37	
_	Feedthrough Noise, Control to Switch (Figure 7)	$V_{in} \leq$ 1 MHz Square Wave ( $t_r = t_f = 6$ ns) Adjust R <sub>L</sub> at Setup so that I <sub>S</sub> = 0 A R <sub>L</sub> = 600 $\Omega$ , C <sub>L</sub> = 50 pF	4.5 5.5	100 200	mVpp
		$R_L = 10 \text{ k}\Omega$ , $C_L = 10 \text{ pF}$	4.5 5.5	50 100	
_	Crosstalk Between Any Two Switches (Figure 12)	$ \begin{aligned} f_{\text{in}} &\equiv \text{Sine Wave} \\ \text{Adjust } f_{\text{in}} &\text{ Voltage to Obtain 0 dBm at V}_{\text{IS}} \\ f_{\text{in}} &= 10 \text{ kHz, R}_{\text{L}} = 600 \ \Omega, C_{\text{L}} = 50 \text{ pF} \end{aligned} $	4.5 5.5	- 70 - 70	dB
		$f_{in}$ = 1.0 MHz, $R_L$ = 50 $\Omega$ , $C_L$ = 10 pF	4.5 5.5	- 80 - 80	
THD	Total Harmonic Distortion (Figure 14)	$f_{\text{in}} = 1 \text{ kHz}, R_{\text{L}} = 10 \text{ k}\Omega, C_{\text{L}} = 50 \text{ pF}$ $\text{THD} = \text{THD}_{\text{Measured}} - \text{THD}_{\text{Source}}$ $\text{V}_{\text{IS}} = 4.0 \text{ Vpp sine wave}$ $\text{V}_{\text{IS}} = 5.0 \text{ Vpp sine wave}$	4.5 5.5	0.10 0.06	%

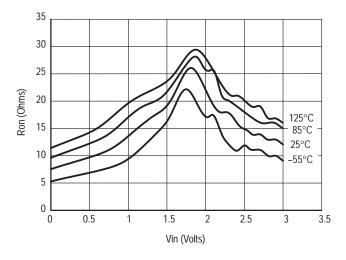
<sup>\*</sup>Guaranteed limits not tested. Determined by design and verified by qualification.



400 350 300 250 200 150 100 50 0 0.5 1 1.5 2 2.5 Vin (Volts)

Figure 1a. Typical On Resistance,  $V_{CC} = 2.0 \text{ V}$ ,  $T = 25^{\circ}\text{C}$ 

Figure 1b. Typical On Resistance, V<sub>CC</sub> = 2.0 V



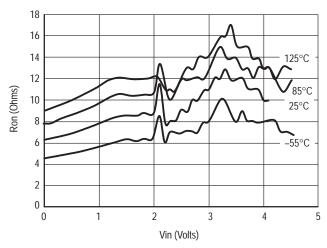
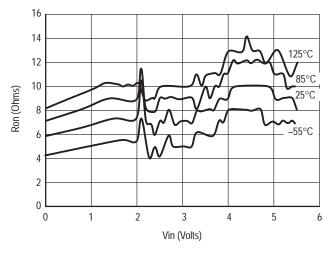


Figure 1c. Typical On Resistance,  $V_{CC} = 3.0 \text{ V}$ 

Figure 1d. Typical On Resistance,  $V_{CC} = 4.5 \text{ V}$ 



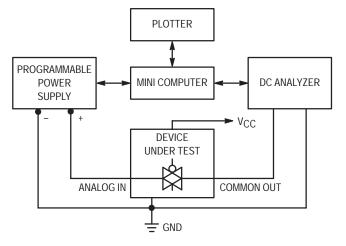


Figure 1e. Typical On Resistance, V<sub>CC</sub> = 5.5 V

Figure 2. On Resistance Test Set-Up

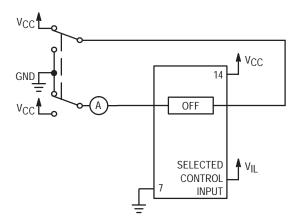


Figure 3. Maximum Off Channel Leakage Current, Any One Channel, Test Set-Up

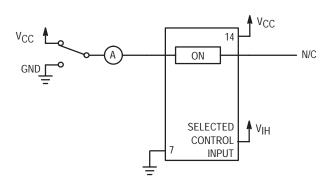
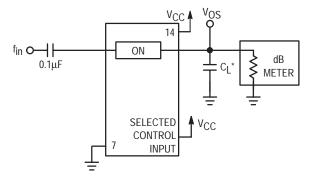
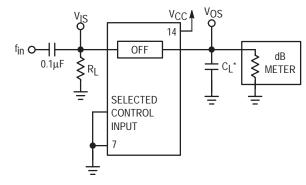


Figure 4. Maximum On Channel Leakage Current, Test Set-Up



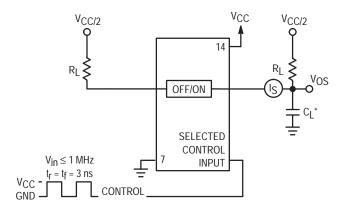
\*Includes all probe and jig capacitance.

Figure 5. Maximum On–Channel Bandwidth
Test Set–Up



\*Includes all probe and jig capacitance.

Figure 6. Off-Channel Feedthrough Isolation, Test Set-Up



 ${}^* Includes \, all \, probe \, and \, jig \, capacitance. \,$ 

Figure 7. Feedthrough Noise, ON/OFF Control to Analog Out, Test Set-Up

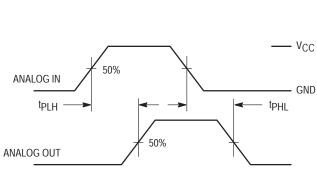
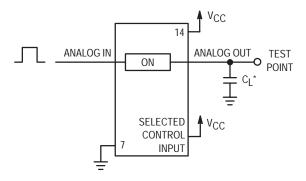
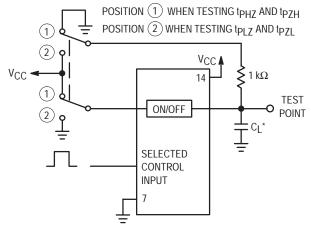


Figure 8. Propagation Delays, Analog In to Analog Out



<sup>\*</sup>Includes all probe and jig capacitance.

Figure 9. Propagation Delay Test Set-Up



<sup>\*</sup>Includes all probe and jig capacitance.

Figure 11. Propagation Delay Test Set-Up

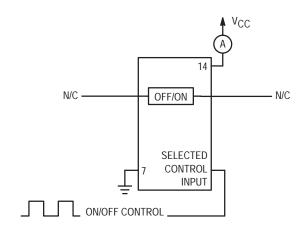


Figure 13. Power Dissipation Capacitance
Test Set-Up

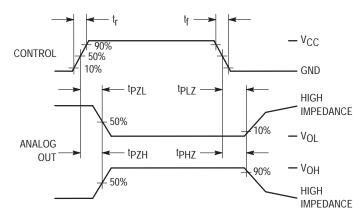
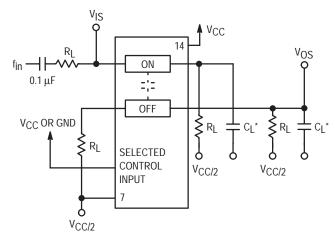
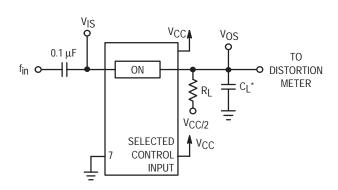


Figure 10. Propagation Delay, ON/OFF Control to Analog Out



\*Includes all probe and jig capacitance.

Figure 12. Crosstalk Between Any Two Switches, Test Set-Up



\*Includes all probe and jig capacitance.

Figure 14. Total Harmonic Distortion, Test Set-Up

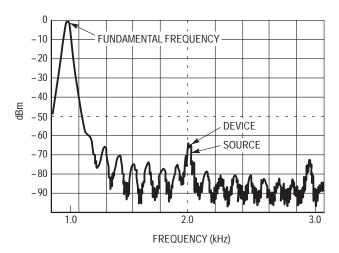


Figure 15. Plot, Harmonic Distortion

#### **APPLICATION INFORMATION**

The ON/OFF Control pins should be at  $V_{CC}$  or GND logic levels,  $V_{CC}$  being recognized as logic high and GND being recognized as a logic low. Unused analog inputs/outputs may be left floating (not connected). However, it is advisable to tie unused analog inputs and outputs to  $V_{CC}$  or GND through a low value resistor. This minimizes crosstalk and feedthrough noise that may be picked—up by the unused I/O pins.

The maximum analog voltage swings are determined by the supply voltages V<sub>CC</sub> and GND. The positive peak analog voltage should not exceed V<sub>CC</sub>. Similarly, the negative peak analog voltage should not go below GND. In the example

below, the difference between V<sub>CC</sub> and GND is six volts. Therefore, using the configuration in Figure 16, a maximum analog signal of six volts peak–to–peak can be controlled.

When voltage transients above V<sub>CC</sub> and/or below GND are anticipated on the analog channels, external diodes (Dx) are recommended as shown in Figure 17. These diodes should be small signal, fast turn—on types able to absorb the maximum anticipated current surges during clipping. An alternate method would be to replace the Dx diodes with MO•sorbs (Motorola high current surge protectors). MO•sorbs are fast turn—on devices ideally suited for precise DC protection with no inherent wear out mechanism.

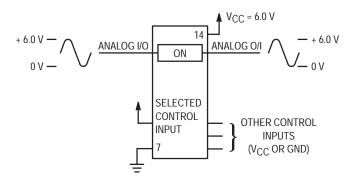


Figure 16. 6.0 V Application

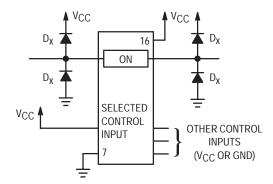


Figure 17. Transient Suppressor Application

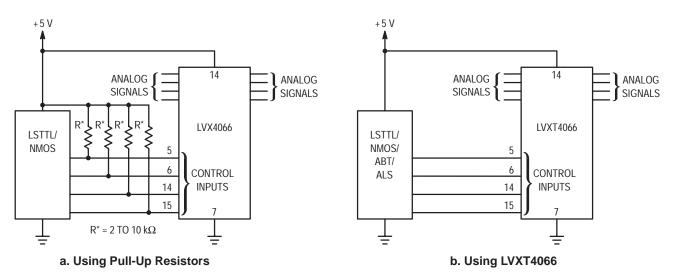


Figure 18. LSTTL/NMOS to CMOS Interface

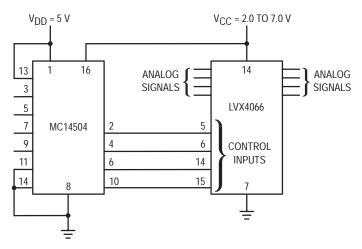


Figure 19. TTL/NMOS-to-CMOS Level Converter Analog Signal Peak-to-Peak Greater than 5 V

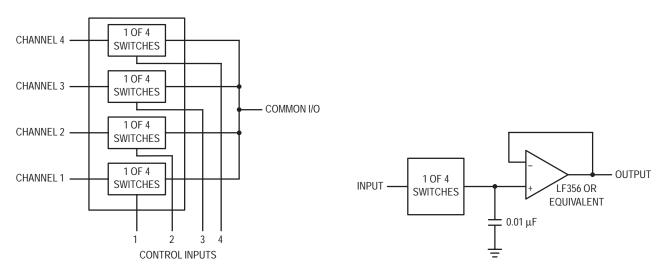
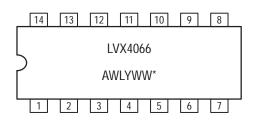


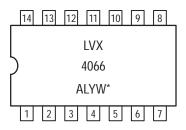
Figure 20. 4-Input Multiplexer

Figure 21. Sample/Hold Amplifier

#### **MARKING DIAGRAMS**

(Top View)





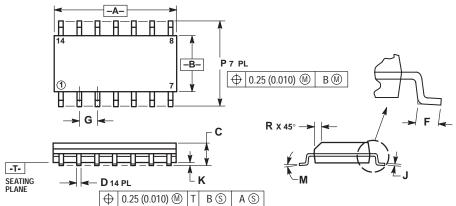
14-LEAD SOIC **D SUFFIX CASE 751A** 

14-LEAD TSSOP **DT SUFFIX CASE 948G** 

\*See Applications Note #AND8004/D for date code and traceability information.

#### **PACKAGE DIMENSIONS**

#### **D SUFFIX** PLASTIC SOIC PACKAGE CASE 751A-03 ISSUE F



#### NOTES:

- NOTES:

  1 DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

  2 CONTROLLING DIMENSION: MILLIMETER.

  3 DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION.

  4 MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.

  5 DIMENSION D DOES NOT INCLUDE DAMBAR

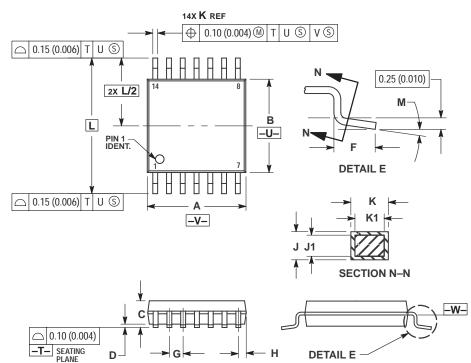
- PROTRUSION. ALLOWABLE DAMBAR
  PROTRUSION. SHALL BE 0.127 (0.005) TOTAL
  IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.

	MILLIMETERS		INC	HES
DIM	MIN	MAX	MIN	MAX
Α	8.55	8.75	0.337	0.344
В	3.80	4.00	0.150	0.157
С	1.35	1.75	0.054	0.068
D	0.35	0.49	0.014	0.019
F	0.40	1.25	0.016	0.049
G	1.27	BSC	0.050	BSC
J	0.19	0.25	0.008	0.009
K	0.10	0.25	0.004	0.009
M	0°	7°	0°	7°
P	5.80	6.20	0.228	0.244
R	0.25	0.50	0.010	0.019

#### **PACKAGE DIMENSIONS**

#### **DT SUFFIX**

PLASTIC TSSOP PACKAGE CASE 948G-01 **ISSUE O** 



- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
   CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH OR GATE BURRS SHALL NOT EXCEED 0.15
- 0.006) PER SIDE.
  DIMENSION B DOES NOT INCLUDE INTERLEAD
  FLASH OR PROTRUSION. INTERLEAD FLASH OR
  PROTRUSION SHALL NOT EXCEED
- PROTROSION SALE NOT EXCEED
  0.25 (0.010) PER SIDE.
  DIMENSION K DOES NOT INCLUDE DAMBAR
  PROTRUSION. ALLOWABLE DAMBAR
  PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN
  EXCESS OF THE K DIMENSION AT MAXIMUM
  MATERIAL CONDITION.
- TERMINAL NUMBERS ARE SHOWN FOR
- REFERENCE ONLY.
  DIMENSION A AND B ARE TO BE DETERMINED AT DATUM PLANE -W-.

	MILLIN	IETERS	INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.90	5.10	0.193	0.200
В	4.30	4.50	0.169	0.177
С		1.20		0.047
D	0.05	0.15	0.002	0.006
F	0.50	0.75	0.020	0.030
G	0.65	BSC	0.026	BSC
Н	0.50	0.60	0.020	0.024
J	0.09	0.20	0.004	0.008
J1	0.09	0.16	0.004	0.006
K	0.19	0.30	0.007	0.012
K1	0.19	0.25	0.007	0.010
L	6.40		0.252 BSC	
M	0°	8°	0°	8°

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